Abstracts

Characteristic-impedance measurement error on lossy substrates

D.F. Williams, U. Arz and H. Grabinski. "Characteristic-impedance measurement error on lossy substrates." 2001 Microwave and Wireless Components Letters 11.7 (Jul. 2001 [MWCL]): 299-301.

This paper examines error caused by parasitic inductance in the characteristic impedance measured by the calibration comparison method on lossy silicon substrates.

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